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X-Ray Spectroscopy for Diagnosis and Analysis

Wednesday, 30 November 2011 09:00 (45 minutes)

X-ray spectroscopy is a powerful tool for diagnosing the emission characteristics of x-ray sources. It may also be used in characterizing the elemental and chemical states present in compound materials, including the spatial distribution of these states. This presentation will describe the appropriate spectroscopic techniques along with examples of their use. The possibility of using laboratory-scale sources, as opposed to synchrotrons, will be discussed, taking into account the signal to noise ratios that are required to provide the necessary precision.

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